16x8 550 MHz Analog Crosspoint Switch, Gain of 1

Check for Samples: LMH6582

FEATURES

- **16 inputs and 8 outputs**
- **64-pin exposed pad TQFP package**
- **−3 dB bandwidth (V_{OUT} = 0.5 V_{PP}) 500 MHz**
- **−3 dB bandwidth (V_{OUT} = 2V_{PP}) 400 MHz**
- **Fast slew rate 2000 V/µs**
- **Low crosstalk (10 MHz/ 100 MHz) −70/ −50 dBc**
- **Easy to use serial programming 4 wire bus**
- **Two programming modes Serial & addressed modes**
- **Symmetrical pinout facilitates expansion.**
- **Output current ±60 mA**
- **Two gain options A_V = 1 or A_V = 2**

APPLICATIONS

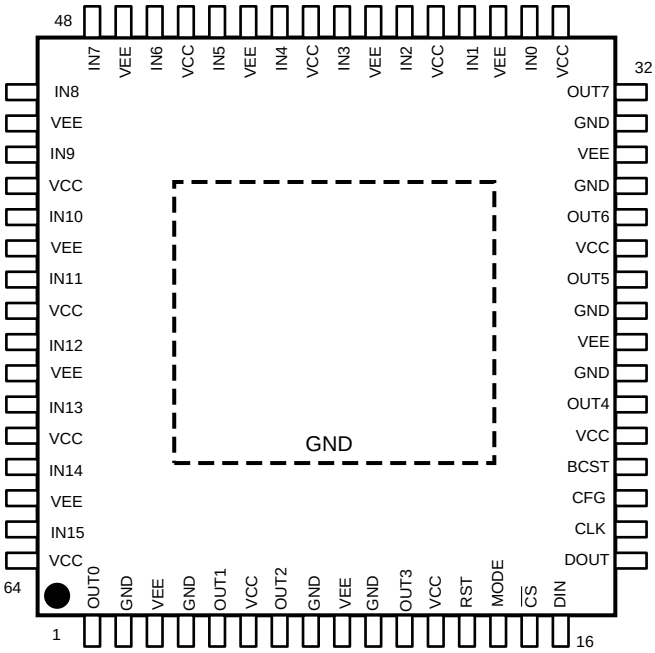
- **Studio monitoring/production video systems**
- **Conference room multimedia video systems**
- **KVM (keyboard video mouse) systems**
- **Security/surveillance systems**
- **Multi antenna diversity radio**
- **Video test equipment**
- **Medical imaging**
- **Wide-band routers & switches**

DESCRIPTION

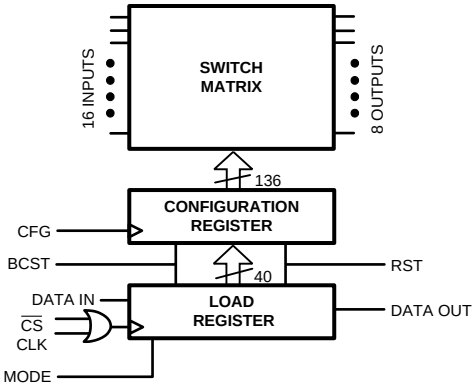
The LMH™ family of products is joined by the LMH6582, a high speed, non-blocking, analog, crosspoint switch. The LMH6582 is designed for high speed, DC coupled, analog signals like high resolution video (UXGA and higher). The LMH6582 has 16 inputs and 8 outputs. The non-blocking architecture allows an output to be connected to any input, including an input that is already selected. With fully buffered inputs the LMH6582 can be impedance matched to nearly any source impedance. The buffered outputs of the LMH6582 can drive up to two back terminated video loads (75Ω load). The outputs and inputs also feature high impedance inactive states allowing high performance input and output expansion for array sizes such as 16 x 16 or 32 x 8 by combining two devices. The LMH6582 is controlled with a 4 pin serial interface. Both single serial mode and addressed chain modes are available.

The LMH6582 comes in a 64-pin thermally enhanced TQFP package. It also has diagonally symmetrical pin assignments to facilitate double sided board layouts and easy pin connections for expansion. The package has an exposed thermal pad on the bottom of the package.

Connection Diagram



Block Diagram



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings (1)

ESD Tolerance(2)	
Human Body Model	2000V
Machine Model	200V
V_S	±6V
I_{IN} (Input Pins)	±20 mA
I_{OUT}	(3)
Input Voltage Range	V^- to V^+
Maximum Junction Temperature	+150°C
Storage Temperature Range	−65°C to +150°C
Soldering Information	
Infrared or Convection (20 sec.)	235°C
Wave Soldering (10 sec.)	260°C

(1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is intended to be functional, but specific performance is not guaranteed. For guaranteed specifications, see the Electrical Characteristics tables.
(2) Human Body Model, applicable std. MIL-STD-883, Method 3015.7. Machine Model, applicable std. JESD22-A115-A (ESD MM std. of JEDEC) Field-Induced Charge-Device Model, applicable std. JESD22-C101-C (ESD FICDM std. of JEDEC).
(3) The maximum output current (I_{OUT}) is determined by device power dissipation limitations.

Operating Ratings (1)

Temperature Range (2)	−40°C to +85°C	
Supply Voltage Range	±3V to ±5.5V	
Thermal Resistance	θ_{JA}	θ_{JC}
64-Pin Exposed Pad TQFP	27°C/W	0.82°C/W

(1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is intended to be functional, but specific performance is not guaranteed. For guaranteed specifications, see the Electrical Characteristics tables.
(2) The maximum power dissipation is a function of $T_{J(MAX)}$, θ_{JA}. The maximum allowable power dissipation at any ambient temperature is $P_D = (T_{J(MAX)} – T_A)/ \theta_{JA}$. All numbers apply for packages soldered directly onto a PC Board.

±3.3V Electrical Characteristics (1)

Unless otherwise specified, typical conditions are T_A = 25°C, A_V = +1, V_S = ±3.3V, R_L = 100Ω; **Boldface** limits apply at the temperature extremes.

Symbol	Parameter	Conditions	Min (2)	Typ (3)	Max (2)	Units
Frequency Domain Performance						
SSBW	−3 dB Bandwidth	V_{OUT} = 0.5 V_{PP}		425		MHz
LSBW		V_{OUT} = 2 V_{PP}, R_L = 1 kΩ		500		
		V_{OUT} = 2 V_{PP}, R_L = 150 kΩ		450		
GF	0.1 dB Gain Flatness	V_{OUT} = 2 V_{PP}, R_L = 150 kΩ		80		MHz
DG	Differential Gain	R_L =1 50Ω, 3.58 MHz/ 4.43 MHz		0.06		%
DP	Differential Phase	R_L = 150Ω, 3.58 MHz/ 4.43 MHz		0.06		deg
Time Domain Response						
t_r	Rise Time	1V Step, 10% to 90%		1.6		ns
t_f	Fall Time	1V Step, 10% to 90%		1.2		ns
OS	Overshoot	2V Step		4		%
SR	Slew Rate	2 V_{PP}, 40% to 60% (4)		1700		V/µs
Distortion And Noise Response						
HD2	2nd Harmonic Distortion	2 V_{PP}, 10 MHz		−76		dBc
HD3	3rd Harmonic Distortion	2 V_{PP}, 10 MHz)		−76		dBc
e_n	Input Referred Voltage Noise	>1 MHz		12		nV/√Hz
i_n	Input Referred Noise Current	>1 MHz		2		pA/√Hz
	Switching Time			16		ns
XTLK	Crosstalk	All Hostile, f =100 MHz		−50		dBc
ISOL	Off Isolation	f = 100 MHz		−60		dBc
Static, DC Performance						
A_V	Gain		0.994	1.00	1.005	
V_{OS}	Offset Voltage			±4	±17	mV
TCV_{OS}	Output Offset Voltage Average Drift	(5)		19		µV/°C
I_B	Input Bias Current	Non-Inverting (6)		−5		µA
V_O	Output Voltage Range	R_L = 100Ω	±1.24	±1.6		V
		R_L = ∞	±1.25	±1.6		
PSRR	Power Supply Rejection Ratio			45		dB
I_{CC}	Positive Supply Current	R_L = ∞		98	117	mA
I_{EE}	Negative Supply Current	R_L = ∞		92	112	mA
	Tri State Supply Current	RST pin > 2.0V		15	24	mA
Miscellaneous Performance						
R_{IN}	Input Resistance	Non-Inverting		100		kΩ
C_{IN}	Input Capacitance	Non-Inverting		1		pF
R_O	Output Resistance Enabled	Closed Loop, Enabled		300		mΩ
	Output Resistance Disabled	Disabled		70		kΩ

(1) Electrical Table values apply only for factory testing conditions at the temperature indicated. No guarantee of parametric performance is indicated in the electrical tables under conditions different than those tested.
(2) Room Temperature limits are 100% production tested at 25°C. Factory testing conditions result in very limited self-heating of the device such that $T_J = T_A$. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods.
(3) Typical values represent the most likely parametric norm as determined at the time of characterization. Actual typical values may vary over time and will also depend on the application and configuration. The typical values are not tested and are not guaranteed on shipped production material.
(4) Slew Rate is the average of the rising and falling edges.
(5) Drift determined by dividing the change in parameter at temperature extremes by the total temperature change.
(6) Negative input current implies current flowing out of the device.

±3.3V Electrical Characteristics [1] (continued)

Unless otherwise specified, typical conditions are T_A = 25°C, A_V = +1, V_S = ±3.3V, R_L = 100Ω; **Boldface** limits apply at the temperature extremes.

Symbol	Parameter	Conditions	Min [2]	Typ [3]	Max [2]	Units
CMVR	Input Common Mode Voltage Range			±0.8		V
I_O	Output Current	Sourcing, V_O = 0 V		±50		mA
Digital Control						
V_{IH}	Input Voltage High		2.0			V
V_{IL}	Input Voltage Low				0.8	V
V_{OH}	Output Voltage High			>2.2		V
V_{OL}	Output Voltage Low			<0.4		V
T_S	Setup Time			7		ns
T_H	Hold Time			7		ns

±5V Electrical Characteristics (1)

Unless otherwise specified, typical conditions are T_A = 25°C, A_V = +1, V_S = ±5V, R_L = 100Ω; **Boldface** limits apply at the temperature extremes.

Symbol	Parameter	Conditions	Min (2)	Typ (3)	Max (2)	Units
Frequency Domain Performance						
SSBW	−3 dB Bandwidth	V_{OUT} = 0.5 V_{PP} (4)		475		MHz
LSBW		V_{OUT} = 2 V_{PP}, R_L = 1 kΩ		550		
		V_{OUT} = 2 V_{PP}, R_L = 150 kΩ		450		
GF	0.1 dB Gain Flatness	V_{OUT} = 2 V_{PP}, R_L = 150 kΩ		100		MHz
DG	Differential Gain	R_L = 150Ω, 3.58 MHz/ 4.43 MHz		0.05		%
DP	Differential Phase	R_L = 150Ω, 3.58 MHz/ 4.43 MHz		0.05		deg
Time Domain Response						
t_r	Rise Time	2V Step, 10% to 90%		3.1		ns
		2V Step, 10% to 90%		1.6		ns
t_f	Fall Time	1V Step, 10% to 90%		1.6		ns
		1V Step, 10% to 90%		1.2		ns
OS	Overshoot	2V Step		2		%
SR	Slew Rate	2 V_{PP}, 40% to 60% (5)		2000		V/µs
Distortion And Noise Response						
HD2	2nd Harmonic Distortion	2 V_{PP}, 5 MHz		−80		dBc
HD3	3rd Harmonic Distortion	2 V_{PP}, 5 MHz		−70		dBc
e_n	Input Referred Voltage Noise	>1 MHz		12		nV/√Hz
i_n	Input Referred Noise Current	>1 MHz		2		pA/√Hz
	Switching Time			15		ns
XTLK	Crosstalk	All Hostile, f = 100 MHz		−50		dBc
ISOL	Off Isolation	f =1 00 MHz		−65		dBc
Static, DC Performance						
A_V	Gain		0.995	1.00	1.005	
V_{OS}	Offset Voltage			±4	±17	mV
TCV_{OS}	Output Offset Voltage Average Drift	(6)		38		µV/°C
I_B	Input Bias Current	Non-Inverting (7)		−5	−12	µA
TCI_B	Input Bias Current Average Drift	Non-Inverting (6)		−12		nA/°C
V_O	Output Voltage Range	R_L = 100Ω	±2.9	±3.1		V
V_O	Output Voltage Range	R_L = ∞	±2.93	±3.2		V
PSRR	Power Supply Rejection Ratio	R_L = ∞	42	45		dB
I_{CC}	Positive Supply Current	R_L = ∞		110	125	mA
I_{EE}	Negative Supply Current	R_L = ∞		104	120	mA
	Tri State Supply Current	RST pin > 2.0V		20	30	mA
XTLK	DC Crosstalk	DC, Channel to Channel	−58	−90		dBc
ISOL	DC Off Isloation	DC	−60	−90		dBc

(1) Electrical Table values apply only for factory testing conditions at the temperature indicated. No guarantee of parametric performance is indicated in the electrical tables under conditions different than those tested.
(2) Room Temperature limits are 100% production tested at 25°C. Factory testing conditions result in very limited self-heating of the device such that $T_J = T_A$. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods.
(3) Typical values represent the most likely parametric norm as determined at the time of characterization. Actual typical values may vary over time and will also depend on the application and configuration. The typical values are not tested and are not guaranteed on shipped production material.
(4) This parameter is guaranteed by design and/or characterization and is not tested in production.
(5) Slew Rate is the average of the rising and falling edges.
(6) Drift determined by dividing the change in parameter at temperature extremes by the total temperature change.
(7) Negative input current implies current flowing out of the device.

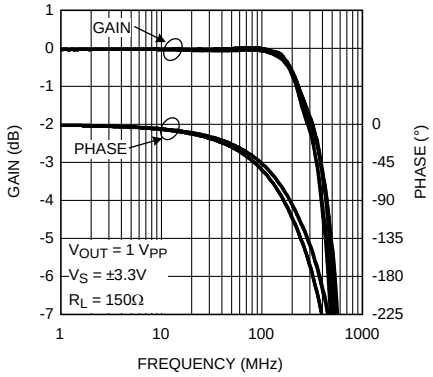
±5V Electrical Characteristics [1] (continued)

Unless otherwise specified, typical conditions are T_A = 25°C, A_V = +1, V_S = ±5V, R_L = 100Ω; **Boldface** limits apply at the temperature extremes.

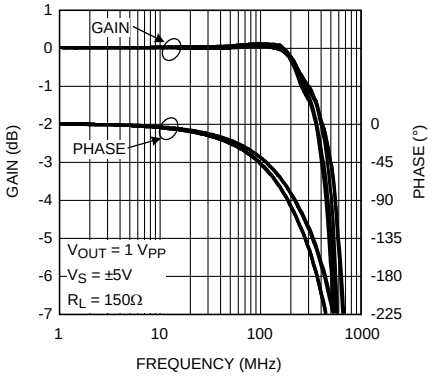
Symbol	Parameter	Conditions	Min [2]	Typ [3]	Max [2]	Units
Miscellaneous Performance						
R_{IN}	Input Resistance	Non-Inverting		100		kΩ
C_{IN}	Input Capacitance	Non-Inverting		1		pF
R_O	Output Resistance	Closed Loop, Enabled		300		mΩ
R_O	Output Resistance	Disabled		70		kΩ
CMVR	Input Common Mode Voltage Range			±3.1		V
I_O	Output Current	Sourcing, V_O = 0 V	±60	±70		mA
Digital Control						
V_{IH}		Input Voltage High	2.0			V
V_{IL}		Input Voltage Low			0.8	V
V_{OH}		Output Voltage High		>2.4		V
V_{OL}		Output Voltage Low		<0.4		V
T_S		Setup Time		5		ns
T_H		Hold Time		5		ns

Typical Performance Characteristics

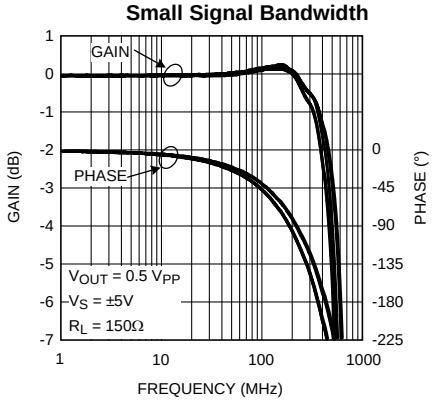
1 V_{PP} Bandwidth



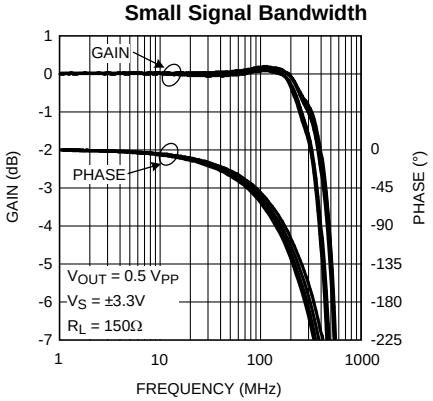
1 V_{PP} Bandwidth



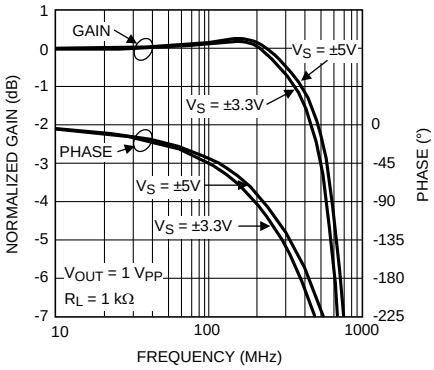
Small Signal Bandwidth



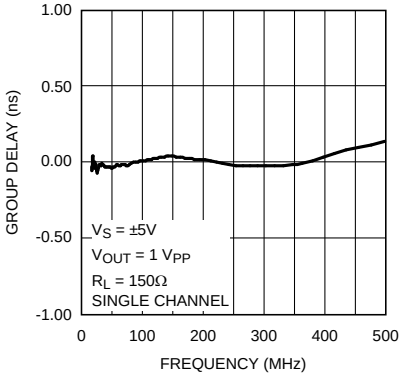
Small Signal Bandwidth



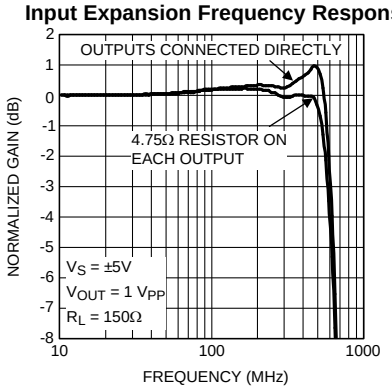
Frequency Response 1 kΩ Load



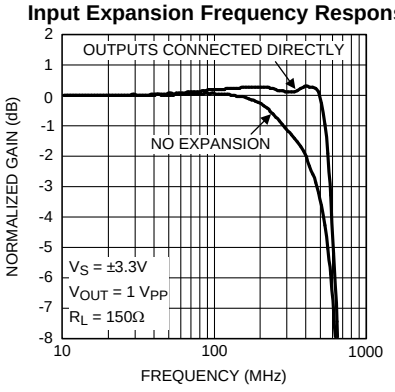
Group Delay



Input Expansion Frequency Response

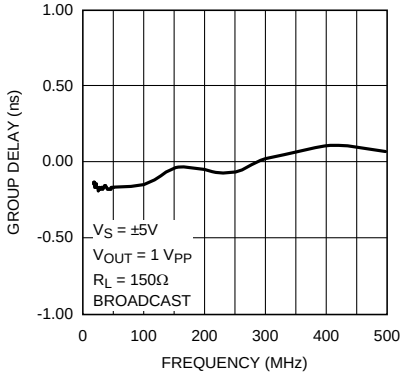


Input Expansion Frequency Response

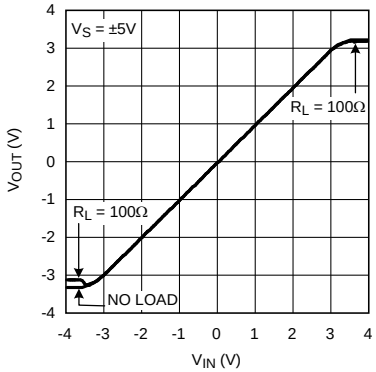


Typical Performance Characteristics (continued)

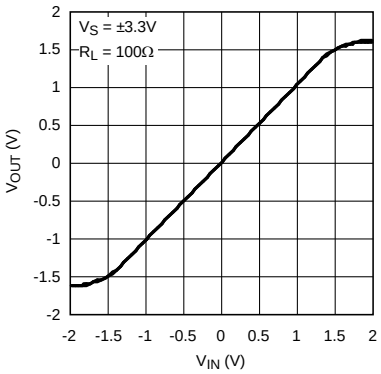
Group Delay



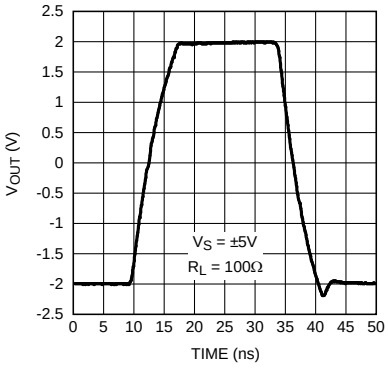
DC Transfer Function



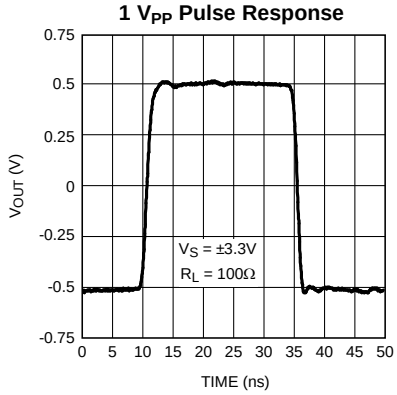
DC Transfer Function



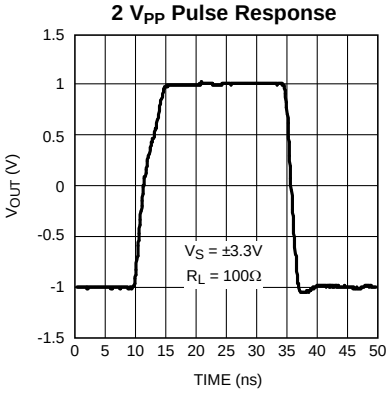
4 V_{PP} Pulse Response



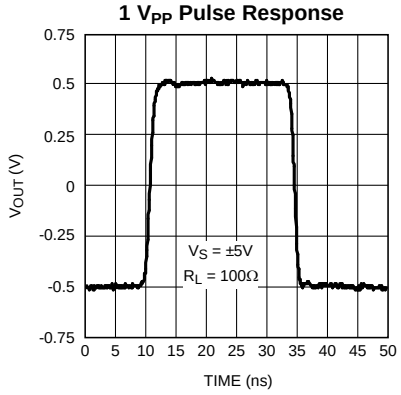
1 V_{PP} Pulse Response



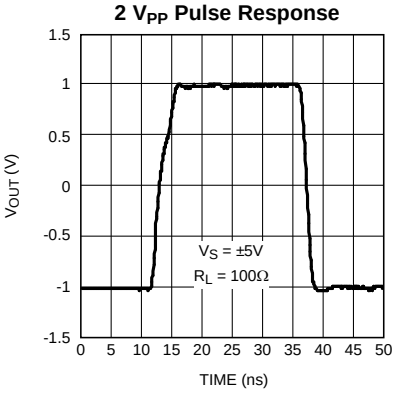
2 V_{PP} Pulse Response



1 V_{PP} Pulse Response

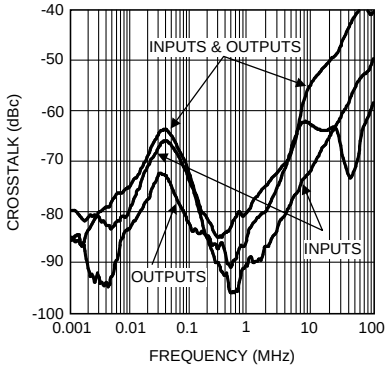


2 V_{PP} Pulse Response

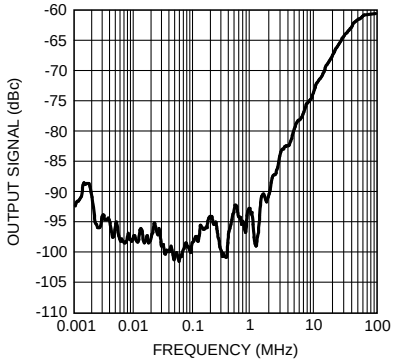


Typical Performance Characteristics (continued)

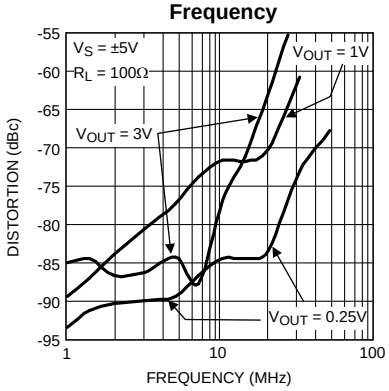
All Hostile



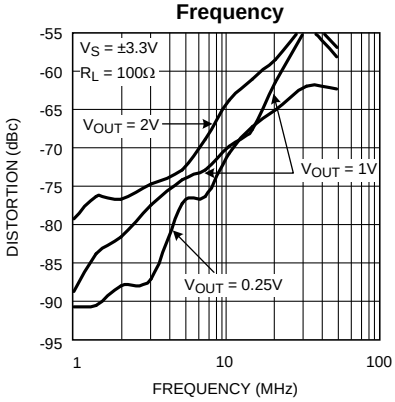
Off Isolation



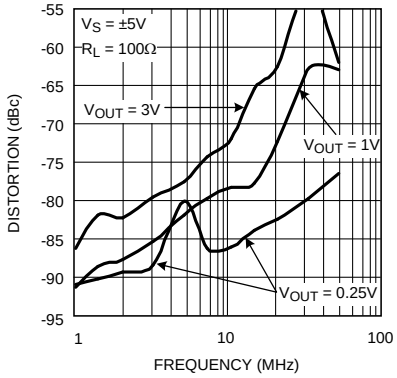
HD3 vs. Frequency



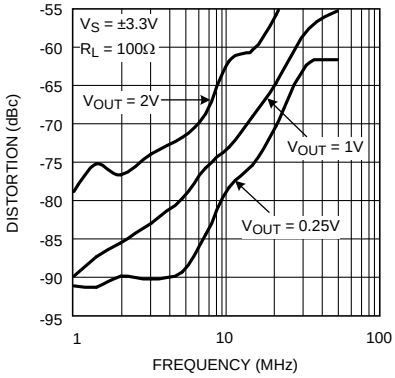
HD2 vs. Frequency



HD2 vs. Frequency

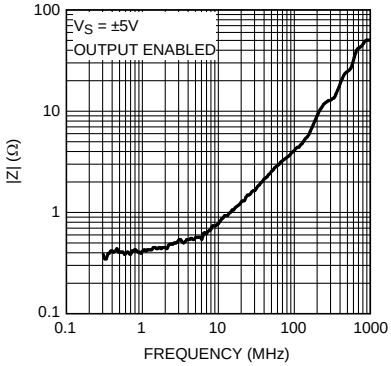


HD3 vs. Frequency

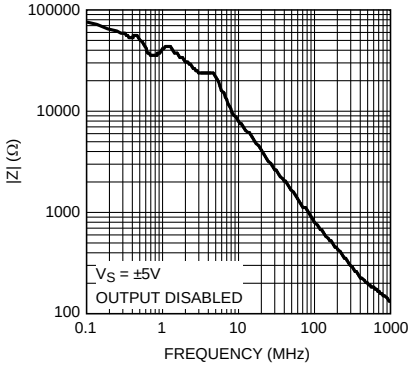


Typical Performance Characteristics (continued)

Enabled Output Impedance



Disabled Output Impedance



Application Section

INTRODUCTION

The LMH6582 is a high speed, fully buffered, non blocking, analog crosspoint switch. Having fully buffered inputs allows the LMH6582 to accept signals from low or high impedance sources without the worry of loading the signal source. The fully buffered outputs will drive 75Ω or 50Ω back terminated transmission lines with no external components other than the termination resistor. The LMH6582 can have any input connected to any (or all) output(s). Conversely, a given output can have only one associated input.

INPUT AND OUTPUT EXPANSION

The LMH6582 has high impedance inactive states for both inputs and outputs allowing maximum flexibility for Crosspoint expansion. In addition the LMH6582 employs diagonal symmetry in pin assignments. The diagonal symmetry makes it easy to use direct pin to pin vias when the parts are mounted on opposite sides of a board. As an example two LMH6582 chips can be combined on one board to form either an 16 x 16 crosspoint or a 32 x 8 crosspoint. To make a 16 x 16 cross-point all 16 input pins would be tied together (Input 0 on side 1 to input 15 on side 2 and so on) while the 8 output pins on each chip would be left separate. To make the 32 x 8 crosspoint, the 8 outputs would be tied together while all 32 inputs would remain independent. In the 32 x 8 configuration it is important not to have 2 connected outputs active at the same time. With the 16 x 16 configuration, on the other hand, having two connected inputs active is a valid state. Crosspoint expansion as detailed above has the advantage that the signal path has only one crosspoint in it at a time. Expansion methods that have cascaded stages will suffer bandwidth loss far greater than the small loading effect of parallel expansion.

Output expansion is very straight forward. Connecting the inputs of two crosspoint switches has a very minor impact on performance. Input expansion requires more planning. As show in Figure 1 and Figure 2 there are two ways to connect the outputs of the crosspoint switches. In Figure 2 the crosspoint switch outputs are connected directly together and share one termination resistor. This is the easiest configuration to implement and has only one drawback. Because the disabled output of the unused crosspoint (only one output can be active at a time) has a small amount of capacitance the frequency response of the active crosspoint will show peaking. This is illustrated in Figure 4 and Figure 5 . In most cases this small amount of peaking is not a problem

As illustrated in Figure 1 each crosspoint output can be given its own termination resistor. This results in a frequency response nearly identical to the non expansion case. There is one drawback for the gain of 2 crosspoint, and that is gain error. With a 75Ω termination resistor the 1250Ω resistance of the disabled crosspoint output will cause a gain error. In order to counter act this the termination resistors of both crosspoints should be adjusted to approximately 71Ω. This will provide very good matching, but the gain accuracy of the system will now be dependent on the process variations of the crosspoint resistors which have a variability of approximately ±20%.

The LMH6582 has fully buffered inputs and outputs. The inputs provide a low load, high impedance input and ensure maximum performance from a variety of signal sources. The fully buffered outputs will drive up to two back terminated video loads. When disabled, the outputs are in a high impedance state. When making thermal calculations the output loading conditions will be a key consideration. Please see the section on thermal management.

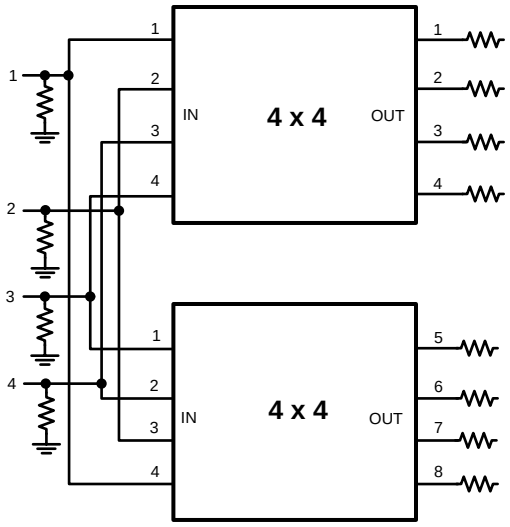


Figure 1. Output Expansion

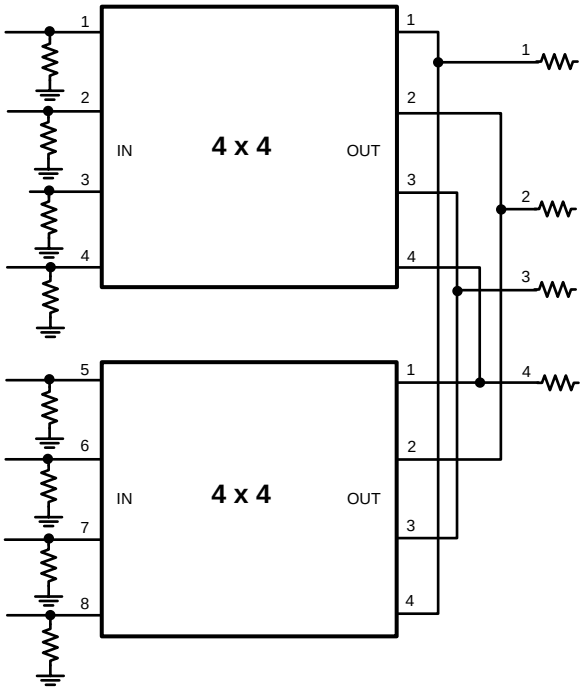


Figure 2. Input Expansion with Shared Termination Resistors

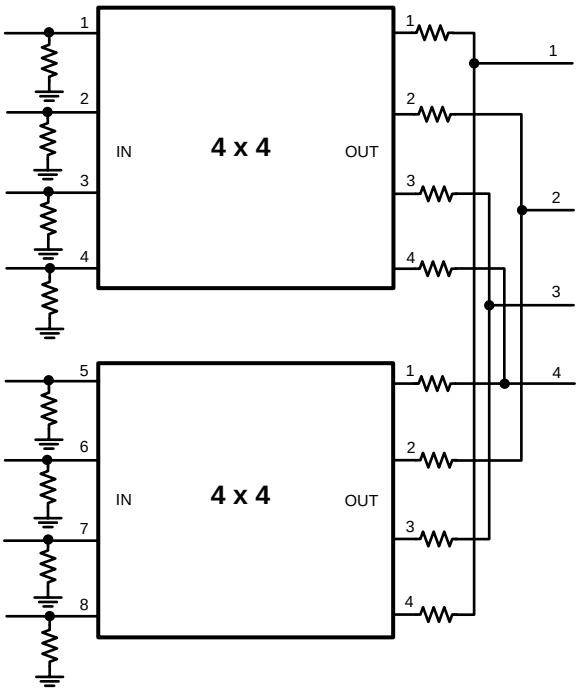


Figure 3. Input Expansion with Separate Termination Resistors

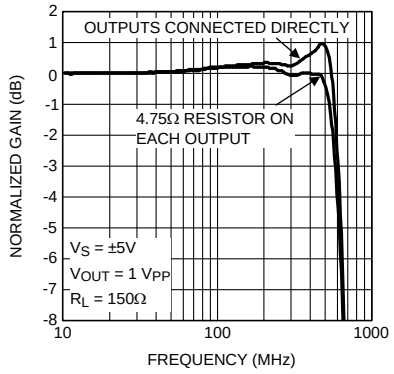


Figure 4. Input Expansion Frequency Response with Direct Connection and Isolation Resistors

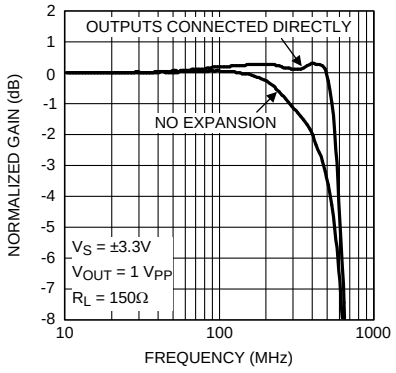


Figure 5. Input Expansion Frequency Response

DRIVING CAPACITIVE LOADS

Capacitive output loading applications will benefit from the use of a series output resistor R_{OUT}. Capacitive loads of 5 pF to 120 pF are the most critical, causing ringing, frequency response peaking and possible oscillation. The chart "Suggested R_{OUT} vs. Cap Load" gives a recommended value for selecting a series output resistor for mitigating capacitive loads. The values suggested in the charts are selected for 0.5 dB or less of peaking in the frequency response. This gives a good compromise between settling time and bandwidth. For applications where maximum frequency response is needed and some peaking is tolerable, the value of R_{OUT} can be reduced slightly from the recommended values. When driving transmission lines the 50Ω or 75Ω matching resistor makes the series output resistor unnecessary.

USING OUTPUT BUFFERING TO ENHANCE BANDWIDTH AND INCREASE RELIABILITY

The LMH6582 crosspoint switch can offer enhanced bandwidth and reliability with the use of external buffers on the outputs. The bandwidth is increased by unloading the outputs and driving the high impedance of an external buffer. See the Frequency Response 1 kΩ Load curve in the Typical Performance section for an example of bandwidth achieved with less loading on the outputs. For this technique to provide maximum benefit a very high speed amplifier such as the LMH6703 should be used. As shown in Figure 6 there is an optional resistor R_{OUT} between the LMH6582 and the buffer input. This resistor will isolate the amplifier input capacitance and board capacitance from the crosspoint switch output. Any traces longer than 1 cm will most likely require some termination resistance as shown.

Besides offering enhanced bandwidth performance, using an external buffer provides for greater system reliability. The first advantage is to reduce thermal loading on the crosspoint switch. This reduced die temperature which increases the life of the crosspoint. The second advantage is enhanced ESD reliability. It is impossible to build high speed devices that can withstand all possible ESD events. With external buffers the crosspoint switch is isolated from ESD events on the external system connectors.

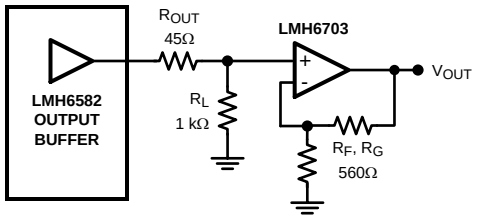


Figure 6. Buffered Output

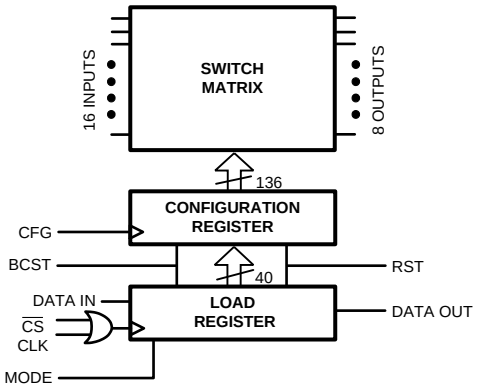
In this example R_{OUT} is to improve settling time by isolating the LMH6703 input capacitance from the crosspoint output. The resistor R_L is optional. It may improve performance by providing a small DC load for the LMH6582 output stage.

CROSSTALK

When designing a large system such as a video router crosstalk can be a very serious problem. Extensive testing in our lab has shown that most crosstalk is related to board layout rather than occurring in the crosspoint switch. There are many ways to reduce board related crosstalk. Using controlled impedance lines is an important step. Using well decoupled power and ground planes will help as well. When crosstalk does occur within the crosspoint switch it self it is often due to signals coupling into the power supply pins. Using appropriate supply bypassing will help to reduce this mode of coupling. Another suggestion is to place as much grounded copper as possible between input and output signal traces. Care must be taken, though, not to influence the signal trace impedances by placing shielding copper too closely. One other caveat to consider is that as shielding materials come closer to the signal trace the trace needs to be smaller to keep the impedance from falling too low. Using thin signal traces will result in unacceptable losses due to resistive losses. This effect becomes even more pronounced at higher frequencies due to the skin effect. The skin effect reduces the effective thickness of the trace as frequency increases. Resistive losses make crosstalk worse because as the desired signal is attenuated with higher frequencies crosstalk increases at higher frequencies.

DIGITAL CONTROL

Figure 7. Block Diagram



The LMH6582 has internal control registers that store the programming states of the crosspoint switch. The logic is two staged to allow for maximum programming flexibility. The first stage of the control logic is tied directly to the crosspoint switching matrix. This logic consists of one register for each output that stores the on/off state and the address of which input to connect to. These registers are not directly accessible by the user. The second level of logic is another bank of registers identical to the first, but set up as shift registers. These registers are accessed by the user via the serial input bus. As described further below, there are two modes for programing the LMH6582, Serial Mode and Addressed Mode.

The LMH6582 is programmed via a serial input bus with the support of 4 other digital control pins. The Serial bus consists of a clock pin (CLK), a serial data in pin (DIN), and a serial data out pin (D_{OUT}). The serial bus is gated by a chip select pin (CS). The chip select pin is active low. While the chip select pin is high all data on the serial input pin and clock pins is ignored. When the chip select pin is brought low the internal logic is set to begin receiving data by the first positive transition (0 to 1) of the clock signal. The chip select pin must be brought low at least 5 ns before the first rising edge of the clock signal. The first data bit is clocked in on the next negative transition (1 to 0). All input data is read from the bus on the negative edge of the clock signal. Once the last valid data has been clocked in, the chip select pin must go high and then the clock signal must make at least one low to high transition. Otherwise invalid data will be clocked into the chip. The data clocked into the chip is not transferred to the crosspoint matrix until the CFG pin is pulsed high. This is the case regardless of the state of the Mode pin. The CFG pin is not dependent on the state of the Chip select pin. If no new data is clocked into the chip subsequent pulses on the CFG pin will have no effect on device operation.

There are two ways to connect the serial data pins. The first way is to control all 4 pins separately, and the second option is to connect the CFG and the CS pins together for a 3 wire interface. The benefit of the 4 wire interface is that the chip can be configured independently of the CS pin. This would be an advantage in a system with multiple crosspoint chips where all of them could be programmed ahead of time and then configured simultaneously. The 4 wire solution is also helpful in a system that has a free running clock on the CLK pin. In this case, the CS pin needs to be brought high after the last valid data bit to prevent invalid data from being clocked into the chip.

The three wire option provides the advantage of one less pin to control at the expense of having less flexibility with the configure pin. One way around this loss of flexibility would be If the clock signal is generated by an FPGA or microcontroller where the clock signal can be stopped after the data is clocked in. In this case the Chip select function is provided by the presence or absence of the clock signal.

The programming format of the incoming serial data is selected by the MODE pin. When the mode pin is HIGH the crosspoint can be programmed one output at a time by entering a string of data that contains the address of the output that is going to be changed (Addressed Mode). When the mode pin is LOW the crosspoint is in Serial Mode. In this mode the crosspoint accepts a 40 bit array of data that programs all of the outputs. In both modes the data fed into the chip does not change the chip operation until the Configure pin is pulsed high. The configure and mode pins are independent of the chip select pin.

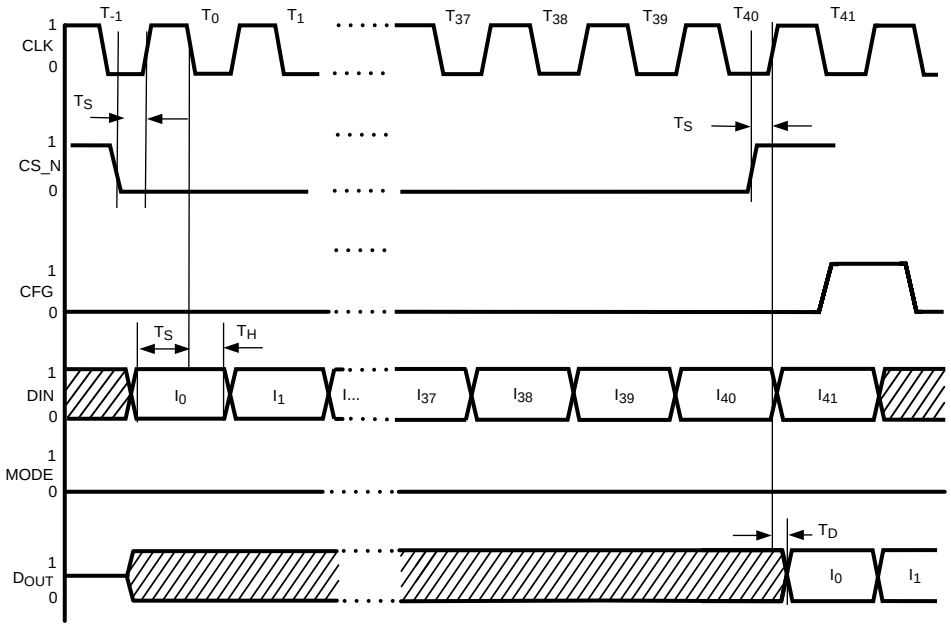


Figure 8. Timing Diagram for Serial Mode

Table 1. Serial Mode Data Frame (First 2 Words)

Output 0					Output 1				
Input Address				On = 0	Input Address				On = 0
LSB			MSB	Off = 1	LSB			MSB	Off = 1
0	1	2	3	4	5	6	7	8	9

Table 2. Serial Mode Data Frame (Continued)

Output 2					Output 3				
Input Address				On = 0	Input Address				On = 0
LSB			MSB	Off = 1	LSB			MSB	Off = 1
10	11	12	13	14	15	16	17	18	19

Table 3. Serial Mode Data Frame (Continued)

Output 4					Output 5				
Input Address				On = 0	Input Address				On = 0
LSB			MSB	Off = 1	LSB			MSB	Off = 1
20	21	22	23	24	25	26	27	28	29

Table 4. Serial Mode Data Frame (Last 2 Words)

Output 6					Output 7				
Input Address				On = 0	Input Address				On = 0
LSB			MSB	Off = 1	LSB			MSB	Off = 1
30	31	32	33	34	35	36	37	38	39

Serial programming mode is the mode selected by bringing the MODE pin low. In this mode a stream of 40 bits programs all 8 outputs of the crosspoint. The data is fed to the chip as shown in the table above. The table is arranged such that the first bit clocked into the crosspoint register is labeled bit number 0. The register labeled Load Register in the block diagram is a shift register. If the chip select pin is left low after the valid data is shifted into the chip and if the clock signal keeps running then additional data will be shifted into the register, and the desired data will be shifted out.

Addressed programming mode makes it possible to change only one output register at a time. To utilize this mode the mode pin must be High. All other pins function the same as in serial programming mode except that the word clocked in is 8 bits and is directed only at the output specified. In addressed mode the data format is shown below in the table titled Table 5.

Timing Diagram

Addressed Mode Timing Diagram

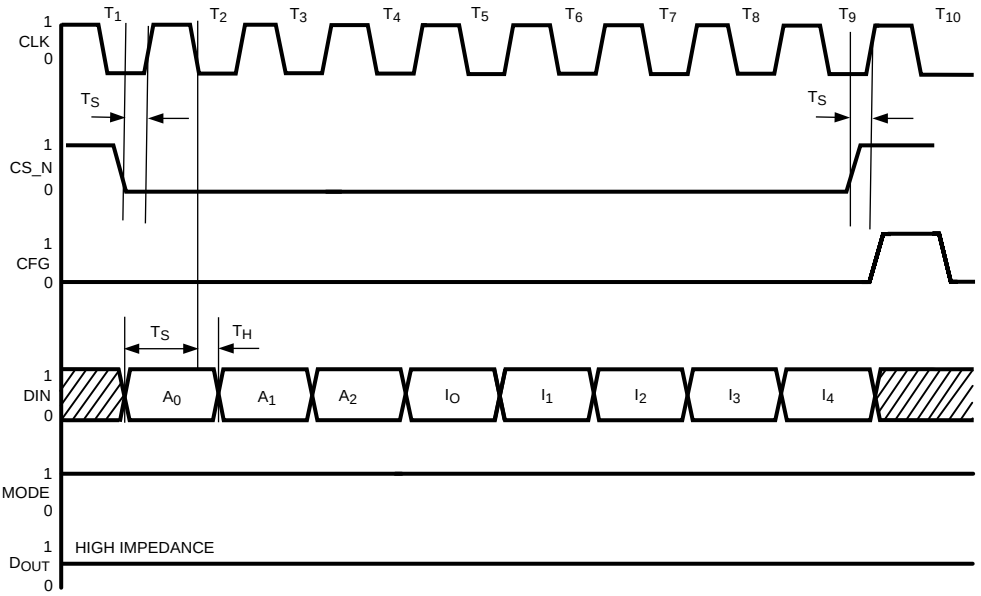


Table 5. Addressed Mode Word Format General Case

Output Address			Input Address				TRI-STATE
LSB		MSB	LSB			MSB	1 = TRI-STATE 0 = On
0	1	2	3	4	5	6	7

DAISY CHAIN OPTION IN SERIAL MODE

The LMH6582 supports daisy chaining of the serial data stream between multiple chips. This feature is available only in the Serial programming mode. To use this feature serial data is clocked into the first chip DIN pin, and the next chip DIN pin is connected to the D_{OUT} pin of the first chip. Both chips may share a chip select signal, or the second chip can be enabled separately. When the chip select pin goes low on both chips a double length word is clocked into the first chip. As the first word is clocking into the first chip the second chip is receiving the data that was originally in the shift register of the first chip. When a full 40 bits have been clocked into the first chip the next clock cycle begins moving the first frame of the new configuration data into the second chip. With a full 80 clock cycles both chips have valid data and the chip select pin of both chips should be brought high to prevent the data from overshooting. A configure pulse will activate the new configuration on both chips simultaneously, or each chip can be configured separately. The mode, chip select, configure and clock pins of both chips can be tied together and driven from the same sources.

SPECIAL CONTROL PINS

The LMH6582 has two special control pins that function independent of the serial control bus. One of these pins is the reset (RST) pin. The RST pin is active high meaning that a logic 1 level the chip is configured with all outputs disabled and in a high impedance state. The RST pin programs all the registers with input address 0 and all the outputs are turned off. In this configuration the device draws only 20 mA. The reset pin can used as a shutdown function to reduce power consumption. The other special control pin is the broadcast (BCST) pin. The BCST pin is also active high and sets all the outputs to the on state connected to input 0. This is sometimes referred to as broadcast mode, where input 0 is broadcast to all 8 outputs.

THERMAL MANAGEMENT

The LMH6582 is packaged in a thermally enhanced Quad Flat Pack package. Even so, it is a high performance device that produces a significant amount of heat. With a ±5V supply, the LMH6582 will dissipate approximately 1.1W of idling power with all outputs enabled. Idling power is calculated based on the typical supply current of 110 mA and a 10V supply voltage. This power dissipation will vary with the range of 800 mW to 1.4W due to process variations. In addition, each equivalent video load (150Ω) connected to the outputs should be budgeted 30 mW of power. For a typical application with one video load for each output this would be a total power of 1.14 W. With a θ_{JA} of 27°C/W this will result in the silicon being 31°C over the ambient temperature. A more aggressive application would be two video loads per output which would result in 1.38W of power dissipation. This would result in a 37°C temperature rise. For heavier loading, the QFP package thermal performance can be significantly enhanced with an external heat sink and by providing for moving air ventilation. Also, be sure to calculate the increase in ambient temperature from all devices operating in the system case. Because of the high power output of this device, thermal management should be considered very early in the design process. Generous passive venting and vertical board orientation may avoid the need for fan cooling or heat sinks. Also, the LMH6582 can be operated with a ±3.3V power supply. This will cut power dissipation substantially while only reducing bandwidth by about 10% (2 V_{PP} output). The LMH6582 is fully characterized and factory tested at the ±3.3V power supply condition for applications where reduced power is desired.

PRINTED CIRCUIT LAYOUT

Generally, a good high frequency layout will keep power supply and ground traces away from the input and output pins. Parasitic capacitances on these nodes to ground will cause frequency response peaking and possible circuit oscillations (see Application Note OA-15 for more information). If digital control lines must cross analog signal lines (particularly inputs) it is best if they cross perpendicularly. National Semiconductor suggests the following evaluation boards as a guide for high frequency layout and as an aid in device testing and characterization:

Device	Package	Evaluation Board Part Number
LMH6582	64-Pin TQFP	LMH730156

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